Search Results -

Terms	Documents
L24 and (relevant near partie\$1)	0

US Pre-Grant Publication Full-Text Database
US Patents Full-Text Database
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EPO Abstracts Database
JPO Abstracts Database
Derwent World Patents Index
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Search:

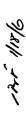
Database:

		Refine Search
Recall Text	Clear	Interrupt

Search History

Set Name side by side	Query	Hit Count	Set Name result set
-	B, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=1	YES; OP=OR	
<u>L25</u>	L24 and (relevant near partie\$1)	0	<u>L25</u>
<u>L24</u>	L23 and stage\$1	19	<u>L24</u>
<u>L23</u>	L2 and pointer	60	<u>L23</u>
<u>L22</u>	L21 and pointer	0	<u>L22</u>
<u>L21</u>	L20 and L5	4	<u>L21</u>
<u>L20</u>	709/\$.ccls.	41494	<u>L20</u>
<u>L19</u>	(L17 or L18) and L5	0	<u>L19</u>
<u>L18</u>	717/103.ccls.	92	<u>L18</u>
<u>L17</u>	717/100.ccls.	503	<u>L17</u>
<u>L16</u>	L15 and L5	0	<u>L16</u>
<u>L15</u>	705/29.ccls.	339	<u>L15</u>
<u>L14</u>	L13 and L5	1	<u>L14</u>
<u>L13</u>	709/213-219.ccls.	8994	<u>L13</u>
<u>L12</u>	(L8 or L9 or L10 or L11) and L5	0	<u>L12</u>

L10 700/103-104.ccls. 302 L10 L9 700/106-107.ccls. 195 L9 L8 700/97-98.ccls. 1023 L8 L7 L6 and L5 1 L7 L6 707/\$.ccls. 31824 L6 L5 L3 and (develop\$6 near stage) 57 L5 L4 L3 and (develop\$ near stage) 57 L4 L3 L2 and stage\$1 191 L3 L2 L1 and (shar\$3 same (database or table)) 356 L2 L1 manufactur\$ near component\$1 30808 L1	<u>L11</u>	700/117.ccls.	1052	<u>L11</u>
L8 700/97-98.ccls. 1023 L8 L7 L6 and L5 1 L7 L6 707/\$.ccls. 31824 L6 L5 L3 and (develop\$6 near stage) 57 L5 L4 L3 and (develop\$ near stage) 57 L4 L3 L2 and stage\$1 191 L3 L2 L1 and (shar\$3 same (database or table)) 356 L2	<u>L10</u>	700/103-104.ccls.	302	<u>L10</u>
L7 L6 and L5 1 L7 L6 707/\$.ccls. 31824 L6 L5 L3 and (develop\$6 near stage) 57 L5 L4 L3 and (develop\$ near stage) 57 L4 L3 L2 and stage\$1 191 L3 L2 L1 and (shar\$3 same (database or table)) 356 L2	<u>L9</u>	700/106-107.ccls.	195	<u>L9</u>
L6 707/\$.ccls. 31824 L6 L5 L3 and (develop\$6 near stage) 57 L5 L4 L3 and (develop\$ near stage) 57 L4 L3 L2 and stage\$1 191 L3 L2 L1 and (shar\$3 same (database or table)) 356 L2	<u>L8</u>	700/97-98.ccls.	1023	<u>L8</u>
L5 L3 and (develop\$6 near stage) 57 L5 L4 L3 and (develop\$ near stage) 57 L4 L3 L2 and stage\$1 191 L3 L2 L1 and (shar\$3 same (database or table)) 356 L2	<u>L7</u>	L6 and L5	1	<u>L7</u>
L4 L3 and (develop\$ near stage) 57 L4 L3 L2 and stage\$1 191 L3 L2 L1 and (shar\$3 same (database or table)) 356 L2	<u>L6</u>	707/\$.ccls.	31824	<u>L6</u>
L3 L2 and stage\$1 191 L3 L2 L1 and (shar\$3 same (database or table)) 356 L2	<u>L5</u>	L3 and (develop\$6 near stage)	57	<u>L5</u>
L1 and (shar\$3 same (database or table)) 356 L2	<u>L4</u>	L3 and (develop\$ near stage)	57	<u>L4</u>
	<u>L3</u>	L2 and stage\$1	191	<u>L3</u>
$\underline{L1}$ manufactur\$ near component\$1 30808 $\underline{L1}$	<u>L2</u>	L1 and (shar\$3 same (database or table))	356	<u>L2</u>
	<u>L1</u>	manufactur\$ near component\$1	30808	<u>L1</u>



Search Results -

Terms	Documents
L1 and L26	7

US Pre-Grant Publication Full-Text Database
US Patents Full-Text Database
US OCR Full-Text Database
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L27

Search:

		Refine Search
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DB=PGPI	B, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=1	YES; OP=OR	
<u>L27</u>	L1 and L26	7	<u>L27</u>
<u>L26</u>	relevant near partie\$1	368	<u>L26</u>
<u>L25</u>	L24 and (relevant near partie\$1)	0	<u>L25</u>
<u>L24</u>	L23 and stage\$1	19	<u>L24</u>
<u>L23</u>	L2 and pointer	60	<u>L23</u>
<u>L22</u>	L21 and pointer	0	<u>L22</u>
<u>L21</u>	L20 and L5	4	<u>L21</u>
<u>L20</u>	709/\$.ccls.	41494	<u>L20</u>
<u>L19</u>	(L17 or L18) and L5	0	<u>L19</u>
<u>L18</u>	717/103.ccls.	92	<u>L18</u>
<u>L17</u>	717/100.ccls.	503	<u>L17</u>
<u>L16</u>	L15 and L5	. 0	<u>L16</u>
<u>L15</u>	705/29.ccls.	339	<u>L15</u>
<u>L14</u>	L13 and L5	1	<u>L14</u>

<u>L13</u>	709/213-219.ccls.	8994	<u>L13</u>
<u>L12</u>	(L8 or L9 or L10 or L11) and L5	0	<u>L12</u>
<u>L11</u>	700/117.ccls.	1052	<u>L11</u>
<u>L10</u>	700/103-104.ccls.	302	<u>L10</u>
<u>L9</u>	700/106-107.ccls.	195	<u>L9</u>
<u>L8</u>	700/97-98.ccls.	1023	<u>L8</u>
<u>L7</u>	L6 and L5	· 1	<u>L7</u>
<u>L6</u>	707/\$.ccls.	31824	<u>L6</u>
<u>L5</u>	L3 and (develop\$6 near stage)	57	<u>L5</u>
<u>L4</u>	L3 and (develop\$ near stage)	57	<u>L4</u>
<u>L3</u>	L2 and stage\$1	191	<u>L3</u>
<u>L2</u>	L1 and (shar\$3 same (database or table))	356	<u>L2</u>
<u>L1</u>	manufactur\$ near component\$1	30808	<u>L1</u>



Search Results -

Terms	Documents	
L21 and pointer	0	

	US Patents Full-Text Database	
Databass	US OCR Full-Text Database EPO Abstracts Database	
Database:	JPO Abstracts Database	
	Derwent World Patents Index	
	IBM Technical Disclosure Bulletins	
	L22	
Search:		Refine Search
	Recall Text Clear	Interrupt

Search History

Set Name side by side	Query	Hit Count	Set Name result set
DB=PGPI	B, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=	YES; OP=OR	
<u>L22</u>	L21 and pointer	0	<u>L22</u>
<u>L21</u>	L20 and L5	4	<u>L21</u>
<u>L20</u>	709/\$.ccls.	41494	<u>L20</u>
<u>L19</u>	(L17 or L18) and L5	0	<u>L19</u>
<u>L18</u>	717/103.ccls.	92	<u>L18</u>
<u>L17</u>	717/100.ccls.	503	<u>L17</u>
<u>L16</u>	L15 and L5	0	<u>L16</u>
<u>L15</u>	705/29.ccls.	339	<u>L15</u>
<u>L14</u>	L13 and L5	1	<u>L14</u>
<u>L13</u>	709/213-219.ccls.	8994	<u>L13</u>
<u>L12</u>	(L8 or L9 or L10 or L11) and L5	0	<u>L12</u>
<u>L11</u>	700/117.ccls.	1052	<u>L11</u>
<u>L10</u>	700/103-104.ccls.	302	<u>L10</u>
<u>L9</u>	700/106-107.ccls.	195	<u>L9</u>

<u>L8</u>	700/97-98.ccls.	1023	<u>L8</u>
<u>L7</u>	L6 and L5	1	<u>L7</u>
<u>L6</u>	707/\$.ccls.	31824	<u>L6</u>
<u>L5</u>	L3 and (develop\$6 near stage)	57	<u>L5</u>
<u>L4</u>	L3 and (develop\$ near stage)	57	<u>L4</u>
<u>L3</u>	L2 and stage\$1	191	<u>L3</u>
<u>L2</u>	L1 and (shar\$3 same (database or table))	356	<u>L2</u>
<u>L1</u>	manufactur\$ near component\$1	30808	<u>L1</u>

Search Results -

Terms	Documents
L8 and (version same component same implementat\$4)	0

US Pre-Grant Publication Full-Text Database
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Search:

L _. 9			△	Refine Search
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DATE: Wednesday, January 18, 2006 Printable Copy Create Case

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DB=PC	GPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR = YES; OR STAND STANDARD ST	P = OR	
<u>L9</u>	L8 and (version same component same implementat\$4)	0	<u>L9</u>
<u>L8</u>	L6 and (function\$8 near test\$3)	36	<u>L8</u>
<u>L7</u>	L6 and test\$3	57	<u>L7</u>
<u>L6</u>	L5 and implementat\$43	57	<u>L6</u>
<u>L5</u>	L1 and L2 and L4	57	<u>L5</u>
<u>L4</u>	shar\$3 same (database or table)	71565	<u>L4</u>
<u>L3</u>	shar\$3 same (database or table) same (relevant near partie\$1)	8	<u>L3</u>
<u>L2</u>	develop\$6 near stage\$1	33174	<u>L2</u>
<u>L1</u>	manufactur\$3 near component\$1	30662	<u>L1</u>

Search Results -

Terms	Documents
L10 and L3	0

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L11		Refine Search
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Set Nam side by sid		Hit Count	Set Name result set
DB=P	GPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=YES; O.	P=OR	
<u>L11</u>	L10 and L3	0	<u>L11</u>
<u>L10</u>	L8 and version	36	<u>L10</u>
<u>L9</u>	L8 and (version same component same implementat\$4)	0	<u>L9</u>
<u>L8</u>	L6 and (function\$8 near test\$3)	36	<u>L8</u>
<u>L7</u>	L6 and test\$3	57	<u>L7</u>
<u>L6</u>	L5 and implementat\$43	57	<u>L6</u>
<u>L5</u>	L1 and L2 and L4	57	<u>L5</u>
<u>L4</u>	shar\$3 same (database or table)	71565	<u>L4</u>
<u>L3</u>	shar\$3 same (database or table) same (relevant near partie\$1)) 8	<u>L3</u>
<u>L2</u>	develop\$6 near stage\$1	33174	<u>L2</u>
<u>L1</u>	manufactur\$3 near component\$1	30662	<u>L1</u>

Search Results -

Terms	Documents
(L17 or L18) and L5	0

US Pre-Grant Publication Full-Text Database
US Patents Full-Text Database
US OCR Full-Text Database
US OCR Full-Text Database
EPO Abstracts Database
JPO Abstracts Database
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L19

Recall Text
Clear

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Search History

Set Name side by side	Query	Hit Count	Set Name result set
•	B, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=1	ES; OP=OR	
<u>L19</u>	(L17 or L18) and L5	0	<u>L19</u>
<u>L18</u>	717/103.ccls.	92	<u>L18</u>
<u>L17</u>	717/100.ccls.	503	<u>L17</u>
<u>L16</u>	L15 and L5	0	<u>L16</u>
<u>L15</u>	705/29.ccls.	339	<u>L15</u>
<u>L14</u>	L13 and L5	1	<u>L14</u>
<u>L13</u>	709/213-219.ccls.	8994	<u>L13</u>
<u>L12</u>	(L8 or L9 or L10 or L11) and L5	0	<u>L12</u>
<u>L11</u>	700/117.ccls.	1052	<u>L11</u>
<u>L10</u>	700/103-104.ccls.	302	<u>L10</u>
<u>L9</u>	700/106-107.ccls.	195	<u>L9</u>
<u>L8</u>	700/97-98.ccls.	1023	<u>L8</u>
<u>L7</u>	L6 and L5	1	<u>L7</u>
<u>L6</u>	707/\$.ccls.	31824	<u>L6</u>

<u>L5</u>	L3 and (develop\$6 near stage)	57	<u>L5</u>
<u>L4</u>	L3 and (develop\$ near stage)	57	<u>L4</u>
<u>L3</u>	L2 and stage\$1	191	<u>L3</u>
<u>L2</u>	L1 and (shar\$3 same (database or table))	356	<u>L2</u>
L1	manufactur\$ near component\$1	30808	L1

Search Results -

Terms	Documents	
L10 and partie	3	

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US Patents Full-Text Database
US OCR Full-Text Database
EPO Abstracts Database
JPO Abstracts Database
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Search:

L12

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Search History

Set Nam side by sid	- · ·	Hit Count S	Set Name result set
DB=P	GPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=YE	S; OP = OR	
<u>L12</u>	L10 and partie	3	<u>L12</u>
<u>L11</u>	L10 and supplier	11	<u>L11</u>
<u>L10</u>	L9 and (develop\$6 near stage)	57	<u>L10</u>
<u>L9</u>	L5 and (develop\$6 same stage)	79	<u>L9</u>
<u>L8</u>	L5 and (develop\$ same stage)	79	<u>L8</u>
<u>L7</u>	L6 not l1	7	<u>L7</u>
<u>L6</u>	L5 and (shar\$3 near (database or table))	7	<u>L6</u>
<u>L5</u>	L4 and stage\$1	191	<u>L5</u>
<u>L4</u>	L3 and (shar\$3 same (database or table))	356	<u>L4</u>
<u>L3</u>	manufactur\$ near component\$1	30808	<u>L3</u>
<u>L2</u>	shar\$3 same (database or table) same ("relevant parties")	8	<u>L2</u>
DB=U	SPT; PLUR=YES; OP=OR		
<u>L1</u>	shar\$3 same (database or table) same ("relevant parties")	3	<u>L1</u>

Search Results -

Terms	Documents
L2 and (relevant near part\$3)	0

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Database:

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14		
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Refine Search





Interrupt

Search History

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Set Name side by side	Query	<u>Hit</u> Count	Set Name result set
DB=P	GPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=YES; OP=OR		
<u>L4</u>	L2 and (relevant near part\$3)	0	<u>L4</u>
<u>L3</u>	L2 and (relevant near part\$)	0	<u>L3</u>
<u>L2</u>	L1 and manufactur\$3	6	<u>L2</u>
<u>L1</u>	(5920873 or 5918232 or 5878408 or 5737581 or 5265004 or 5161101).pn.	12	<u>L1</u>



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"manufactured component" + "development stages" + "sharing



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Feedback Report a problem Satisfaction survey

Terms used manufactured component development stages sharing databse relevant parties testing information

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Relevance scale ...

(ISEF): an integrated industrial-strength software engineering framework

window

Shaye Koenig

November 1988 ACM SIGSOFT Software Engineering Notes, ACM SIGPLAN Notices, Proceedings of the third ACM SIGSOFT/SIGPLAN software engineering symposium on Practical software development environments SDE 3, Volume 13, 24 Issue 5, 2

Publisher: ACM Press

Full text available: pdf(1.34 MB)

Additional Information: full citation, abstract, references, citings, index terms

ISEF is an environment for programming-in-the-large that integrates disparate software engineering principles, methods and tools into an industrial-strength, automated software development framework. Projects using ISEF have reported increased software quality, improved software manageability and decreased software production costs. This paper presents the basic principles and mechanisms that enable ISEF to achieve environment/process integration as well as integration within the environmen ...

2 Producing more reliable software: mature software engineering process vs. state-of-



the-art technology?

James C. Widmaier

June 2000 Proceedings of the 22nd international conference on Software engineering

Publisher: ACM Press

Full text available: pdf(98.31 KB)

Additional Information: full citation, abstract, references, citings, index terms

A customer of high assurance software recently sponsored a software engineering experiment in which a real-time software system was developed concurrently by two popular software development methodologies. One company specialized in the state-ofthe-practice waterfall method rated at a Capability Maturity Model Level 4. A second developer employed his mathematically based formal method with automatic code generation. As specified in separate contracts, C++ code plus development documentatio ...

Keywords: capability maturity model, formal methods, software engineering experiment, software process and product metrics, software reliability

3

<u> </u>	A multidisciplinary approach to improving the user experience: information					
9	development, test, and user experience design teams working together					
	Erin E. Heximer, Uliyana Markova, Lisa Wu, Justine Yoon					
	October 2002 Proceedings of the 20th annual international conference on Computer					
	documentation Publisher: ACM Press					
	Full text available: 📆 pdf(154.76 KB) Additional Information: full citation, abstract, index terms					
	In this paper we discuss how the combined efforts of three teams, Information Development (ID), Test, and User Experience Design (UED), improved the overall customer experience with store development in IBM® WebSphere® Commerce, a software package that enables merchants to host their businesses online. The project began in the spring of 2001 with a formal effort to solicit customer feedback on documentation. A few months later, a test team was created to simulate the customer experience					
	Keywords : cross-functional teams, customer feedback, information, multidisciplinary, testing, user centered design, user-centered design					
4	Analysis of a factory of the future using an integrated set of software for	Г				
٩	for the desired and the second					
V	Masami Shimizu, David Van Zoest					
	December 1988 Proceedings of the 20th conference on Winter simulation					
	Publisher: ACM Press					
	Full text available: pdf(962.87 KB) Additional Information: full citation, abstract, references, citings, index terms					
	Design of a green-field factory, termed a 'factory of the future', proposed by an electrical equipment manufacturer was analyzed using an integrated set of software for manufacturing systems modeling. The analysis involved the following four stages. First, a					

large data base containing part dimensions and processing conditions was analyzed using a spreadsheet software (Lotus 1-2-3) to generate a modeling data base. Second, a roughcut analysis of each manufacturing line in the fac ...

Results 1 - 4 of 4

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"manufactured component" + "development stages" + "sharing

SEARCH



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Results 1 - 1 of 1

Relevance scale

Analysis of a factory of the future using an integrated set of software for

manufacturing systems modeling Masami Shimizu, David Van Zoest

December 1988 Proceedings of the 20th conference on Winter simulation

Publisher: ACM Press

Full text available: pdf(962.87 KB)

Additional Information: full citation, abstract, references, citings, index terms

Design of a green-field factory, termed a 'factory of the future', proposed by an electrical equipment manufacturer was analyzed using an integrated set of software for manufacturing systems modeling. The analysis involved the following four stages. First, a large data base containing part dimensions and processing conditions was analyzed using a spreadsheet software (Lotus 1-2-3) to generate a modeling data base. Second, a roughcut analysis of each manufacturing line in the fac ...

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"sharing database" + "manufactured component" + "developm"

STARCH

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	14 E	4565 of 1	DECHTA	I Halle William	

Feedback Report a problem Satisfaction survey

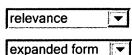
Terms used <u>sharing database manufactured</u> component <u>development stage relevant parties</u>

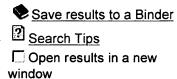
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Relevance scale

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by	J.
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results





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Results 1 - 7 of 7

1 Workflow in different styles of virtual enterprise

Roger Tagg

January 2001 Australian Computer Science Communications, Proceedings of the workshop on Information technology for virtual enterprises ITVE '01, Proceedings of the workshop on Information technology for virtual enterprises ITVE '01, Volume 23 Issue 6

Publisher: IEEE Computer Society , IEEE Computer Society , IEEE Computer Society Press

Full text available: pdf(715.49 KB)

Additional Information: full citation, abstract, references, citings

Because of the many forms a Virtual Enterprise (VE) can take, there is no single model of what type of approach to workflow management is most appropriate. This paper is based on an analysis of the different types of business practice that lead to the formation of VEs. A number of different workflow scenarios are depicted, and four specific issues are then discussed. The first is the recognition of the different life cycle stages of a Virtual Enterprise. The second is the problem of workflow cas ...

Repositories and object oriented databases

Publisher Site

③

Philip A. Bernstein

March 1998 ACM SIGMOD Record, Volume 27 Issue 1

Publisher: ACM Press

Full text available: pdf(87.84 KB) Additional Information: full citation, abstract, citings, index terms

A repository is a shared database of information about engineered artifacts. An object-oriented repository has many of the same features as an object-oriented database: properties, relationships, and versioning. However, the two technologies are different for two reasons. First, a repository system has built-in information models, which are database schemas or object models that cover both generic and tool-specific kinds of information. Second, the features of a repository are often more functio ...

3 Human centered systems in the perspective of organizational and social informatics

Rob Kling, Susan Leigh Star

March 1998 ACM SIGCAS Computers and Society, Volume 28 Issue 1

Publisher: ACM Press

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Analysis of a factory of the future using an integrated set of software for

manufacturing systems modeling Masami Shimizu, David Van Zoest

December 1988 Proceedings of the 20th conference on Winter simulation

Publisher: ACM Press

Full text available: pdf(962.87 KB)

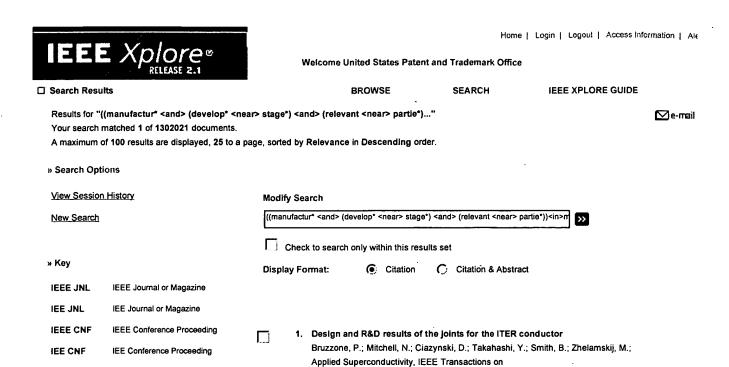
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Design of a green-field factory, termed a 'factory of the future', proposed by an electrical equipment manufacturer was analyzed using an integrated set of software for manufacturing systems modeling. The analysis involved the following four stages. First, a large data base containing part dimensions and processing conditions was analyzed using a spreadsheet software (Lotus 1-2-3) to generate a modeling data base. Second, a roughcut analysis of each manufacturing line in the fac ...

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Volume 7, Issue 2, Part 1, June 1997 Page(s):461 - 464

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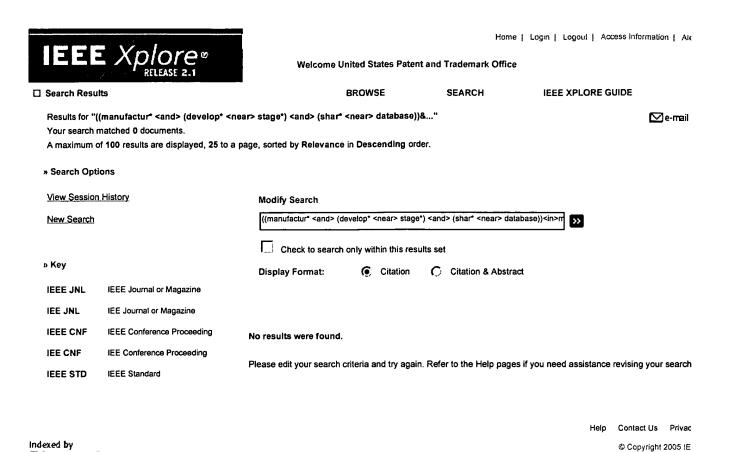
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